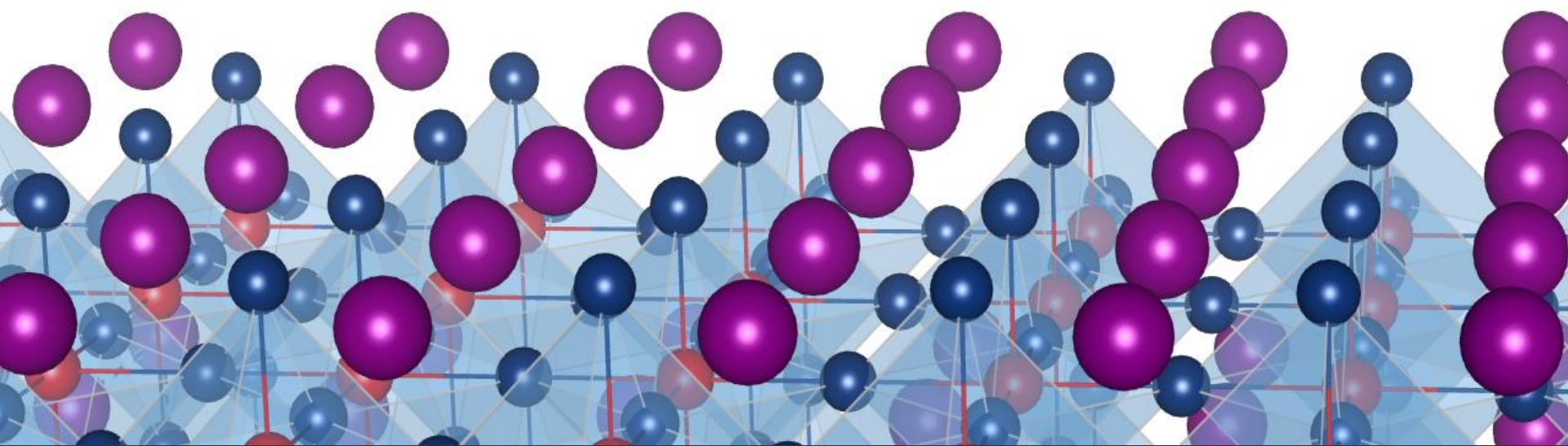
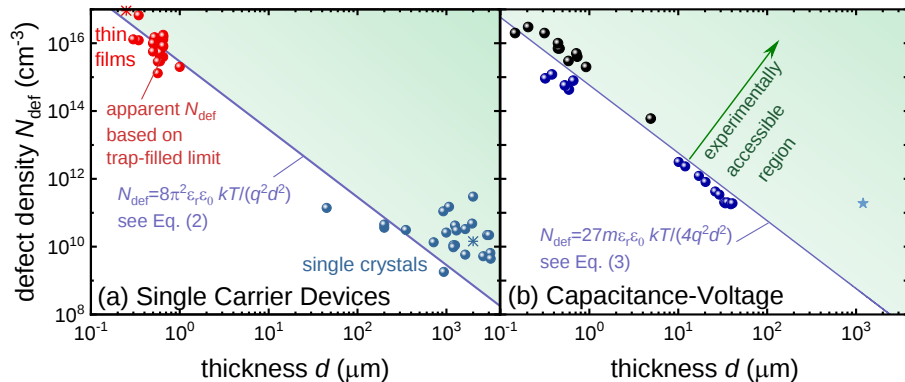




DEFECT DENSITIES AND CHARGE CARRIER LIFETIMES IN LEAD-HALIDE PEROVSKITES

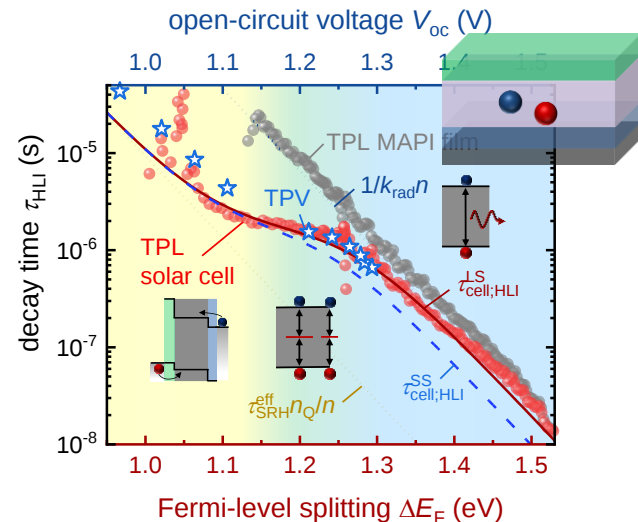
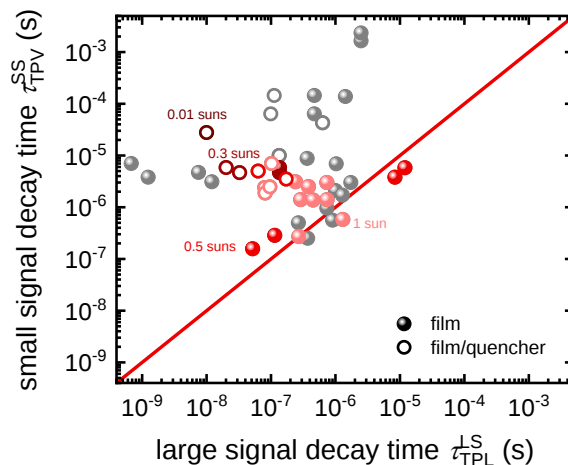
Thomas Kirchartz

IEK-5 Photovoltaik, Forschungszentrum Jülich

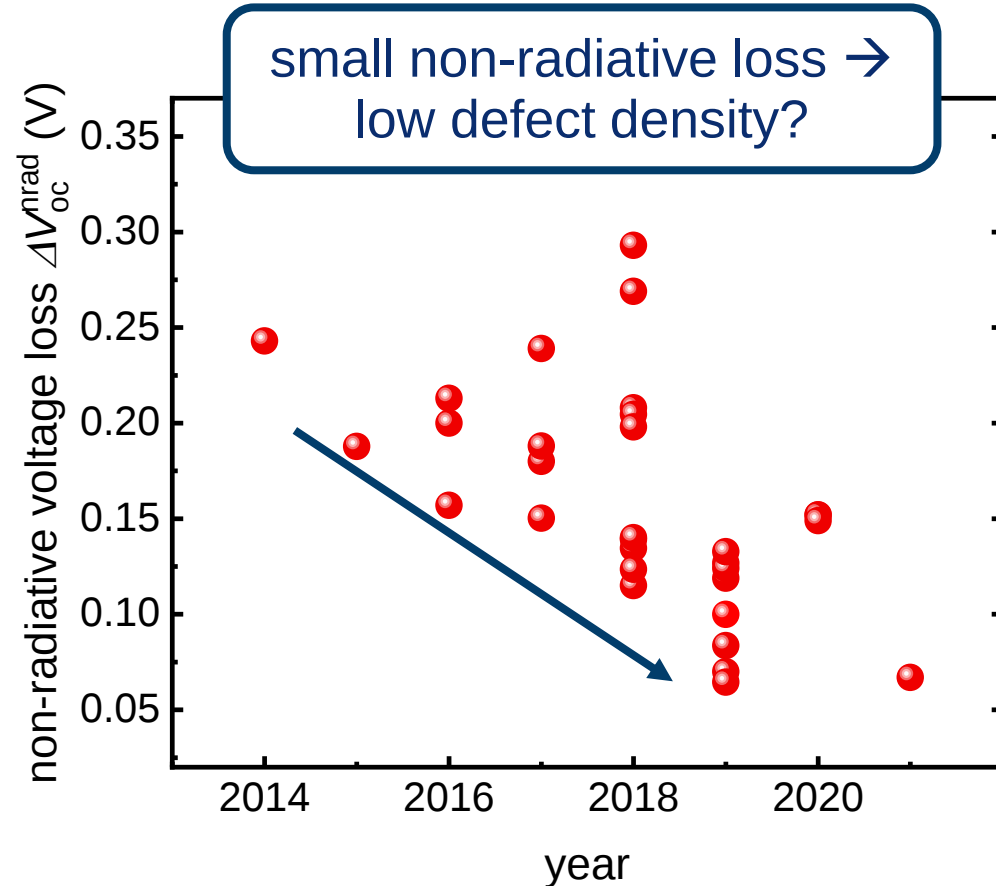


1) Defect densities (and how they change with thickness)

2) “Lifetimes” and how they change with carrier density



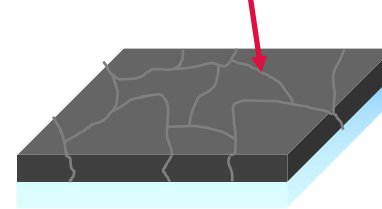
Reduced Non-Radiative Recombination



Thin Film

Single Crystal

defect



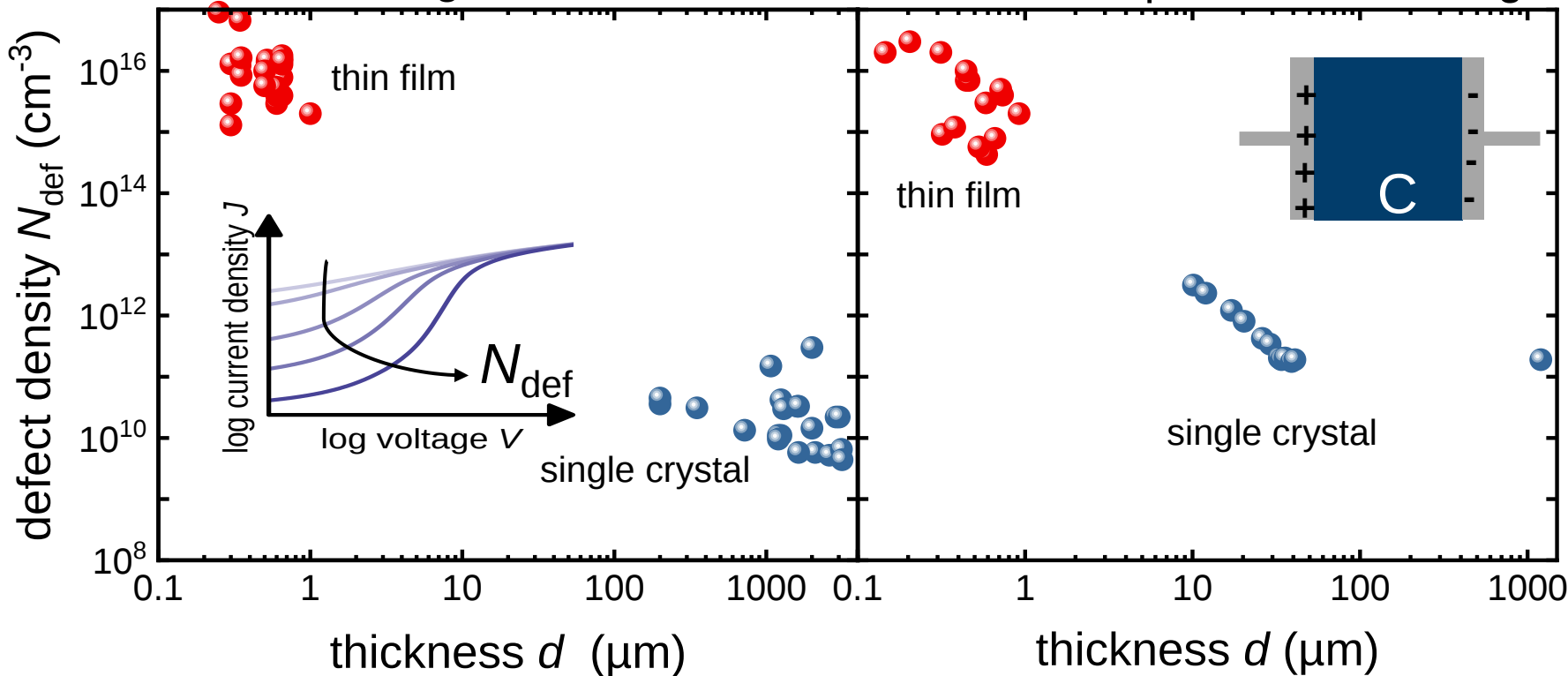
single crystals could have an even
lower defect-density

Apparent Defect Density

Charge sensitive measurements:

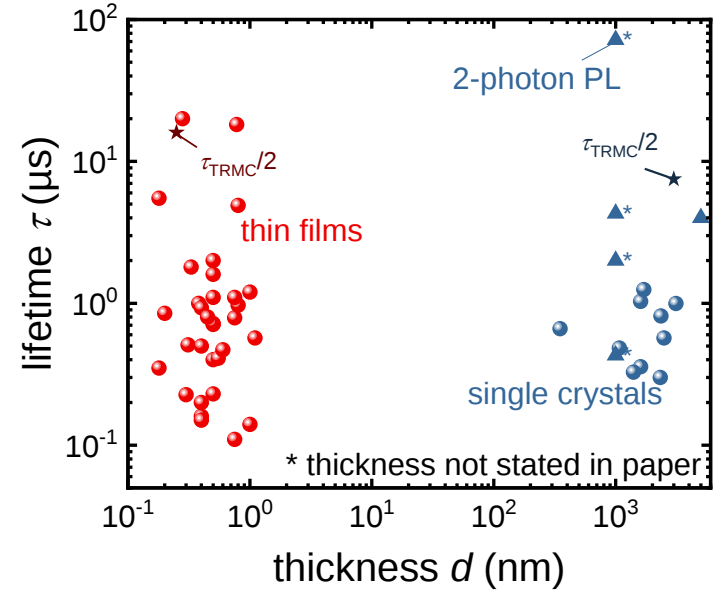
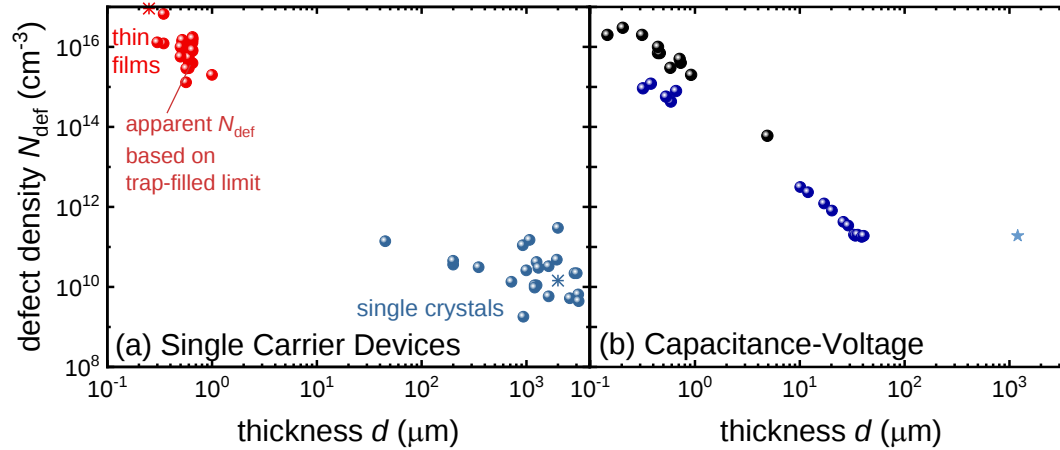
Method 1: Single carrier devices

Method 2: Capacitance – voltage

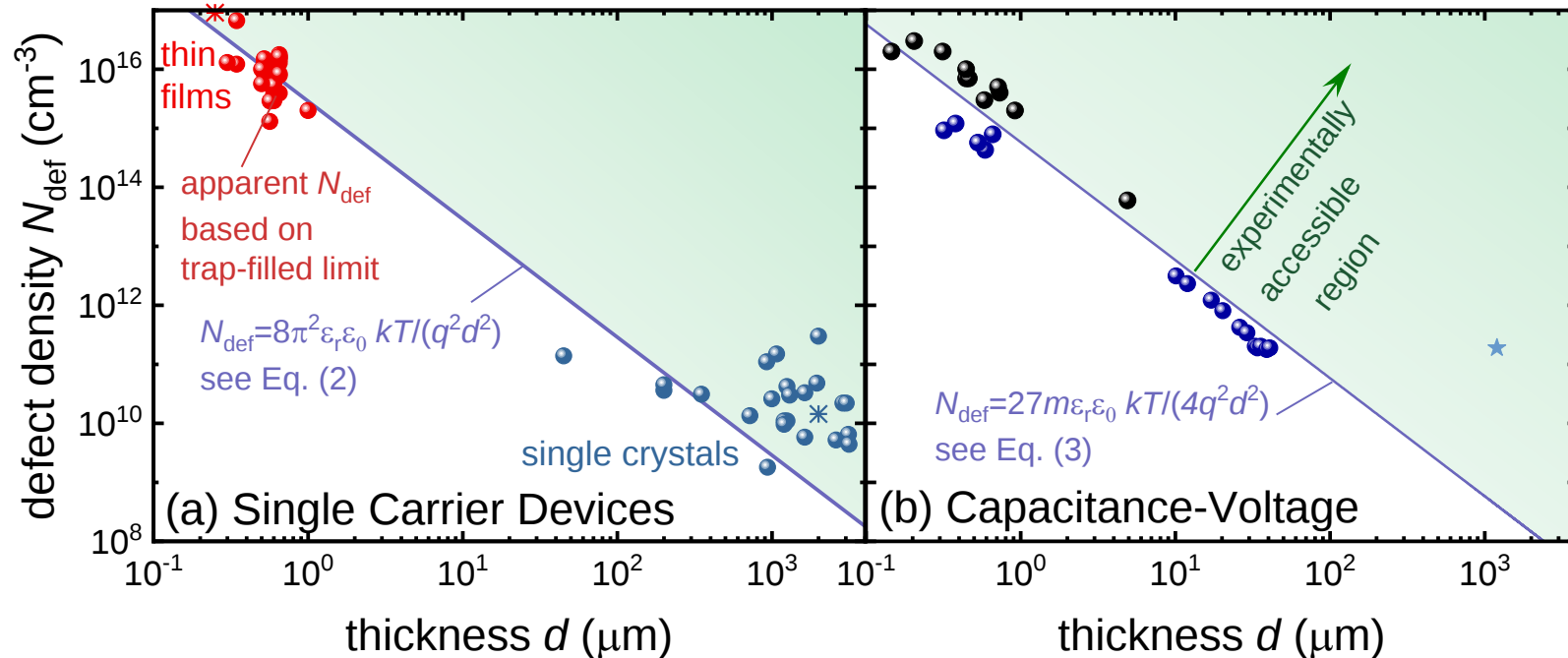


Single crystals much better than thin films

Metaanalysis of trap densities



Sensitivity thresholds for measuring charge densities



Ravishankar et al. Science 371, 6532 (2021), Siekmann et al. ACS Energy Lett. 6, 3244 (2021)

Surface charges compete with the trap charges

The thickness trend explained.

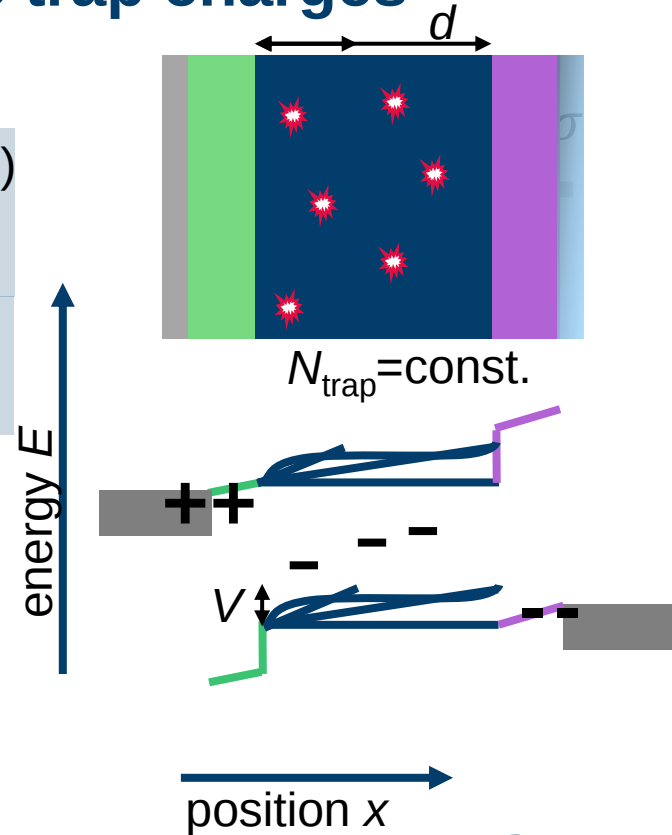
surface charge (C/cm ²)	volume charge (C/cm ³)
$\sigma \ll dqN_{\text{trap}}$	
$\sigma = \frac{\varepsilon V}{d} \ll dqN_{\text{trap}}$	
$\rightarrow \frac{\varepsilon V}{qd^2} \ll N_{\text{trap}}$	

→ higher N_{trap} needed for thinner films

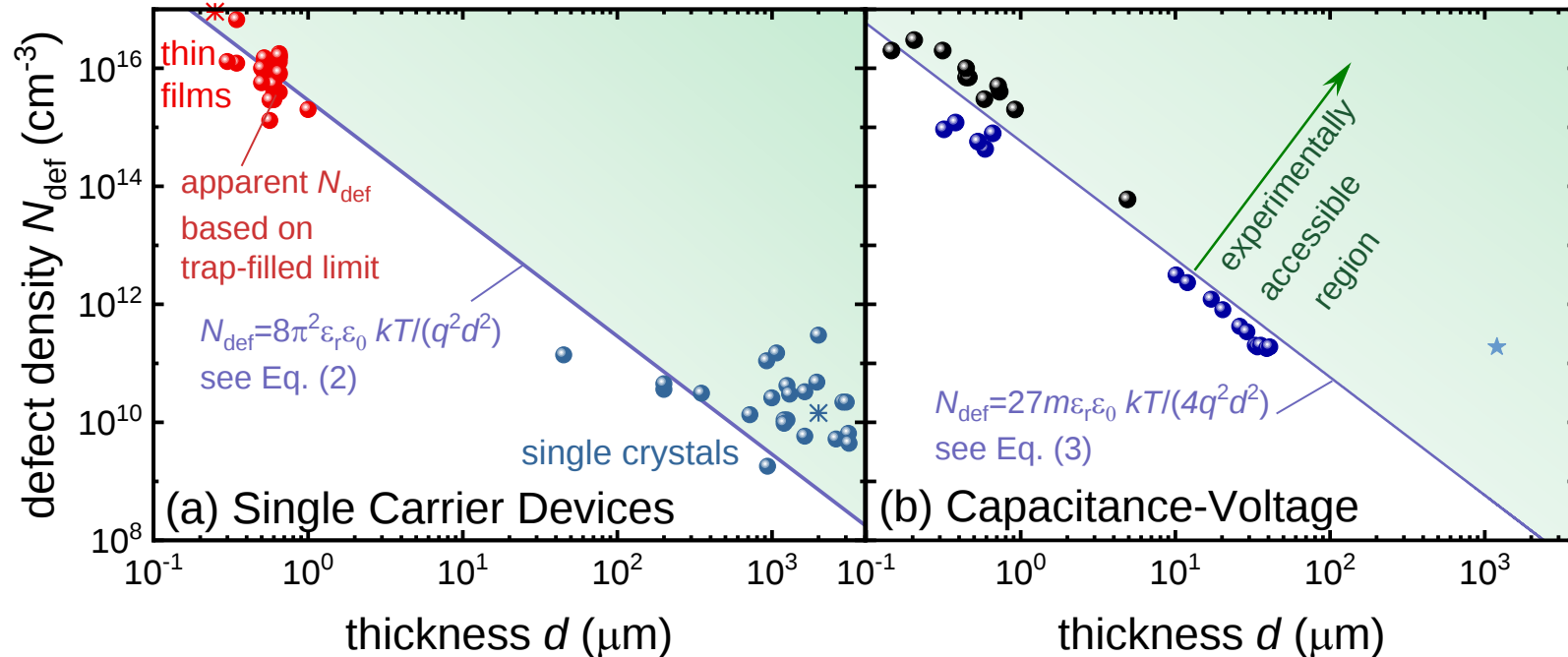
σ : surface charge density

ε : permittivity q : elementary charge

d : thickness



Sensitivity thresholds for measuring charge densities



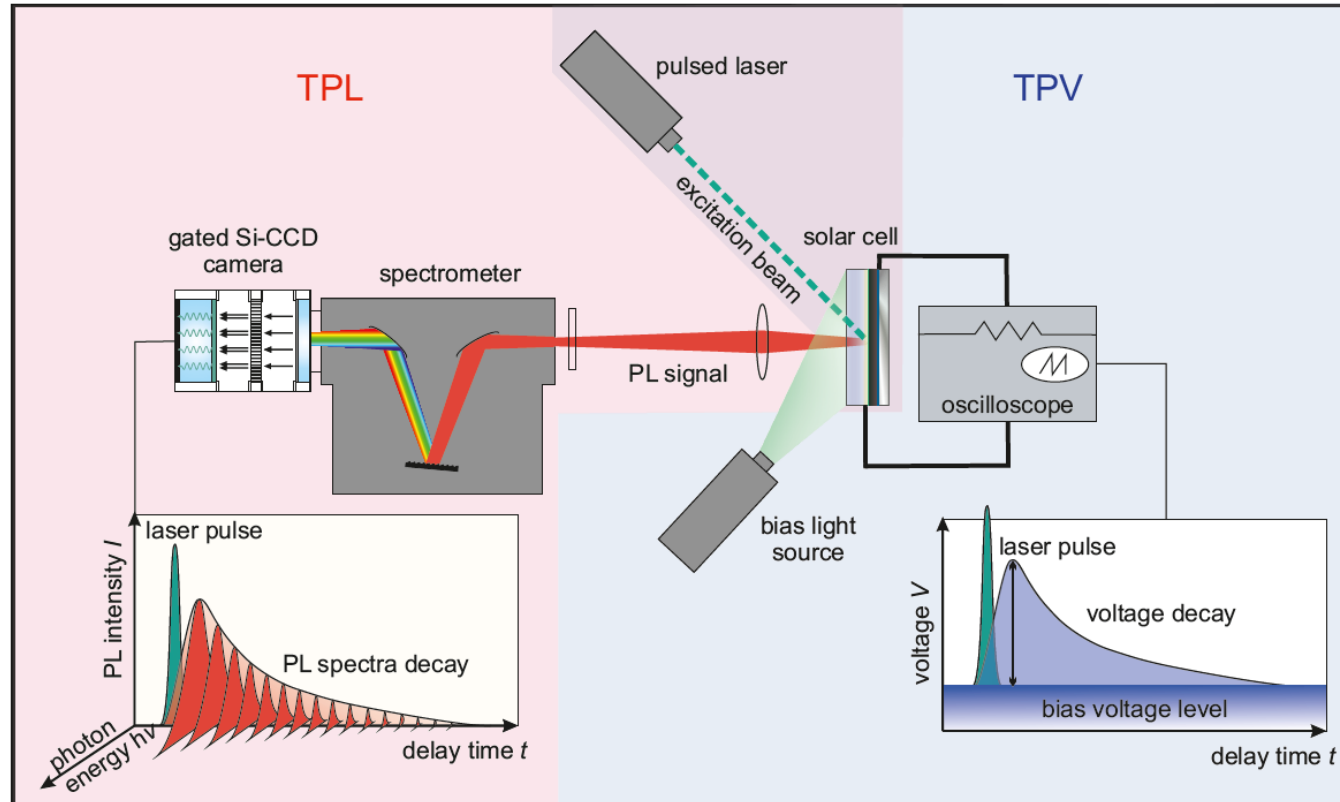
Ravishankar et al. Science 371, 6532 (2021), Siekmann et al. ACS Energy Lett. 6, 3244 (2021)

Transient Photoluminescence (TPL)

measures the luminescence decay

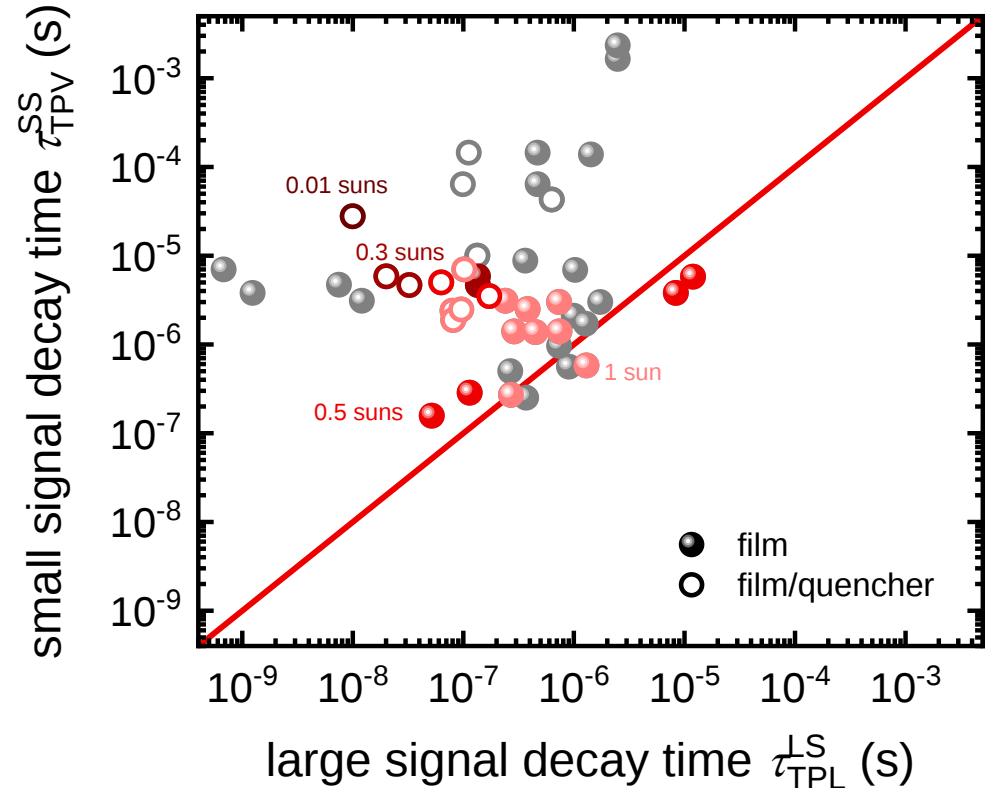
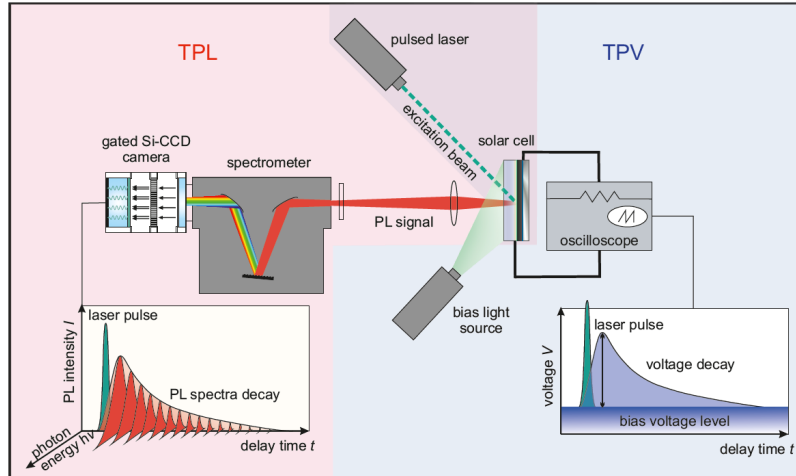
Transient Photovoltage (TPV)

measures the decay of an external voltage



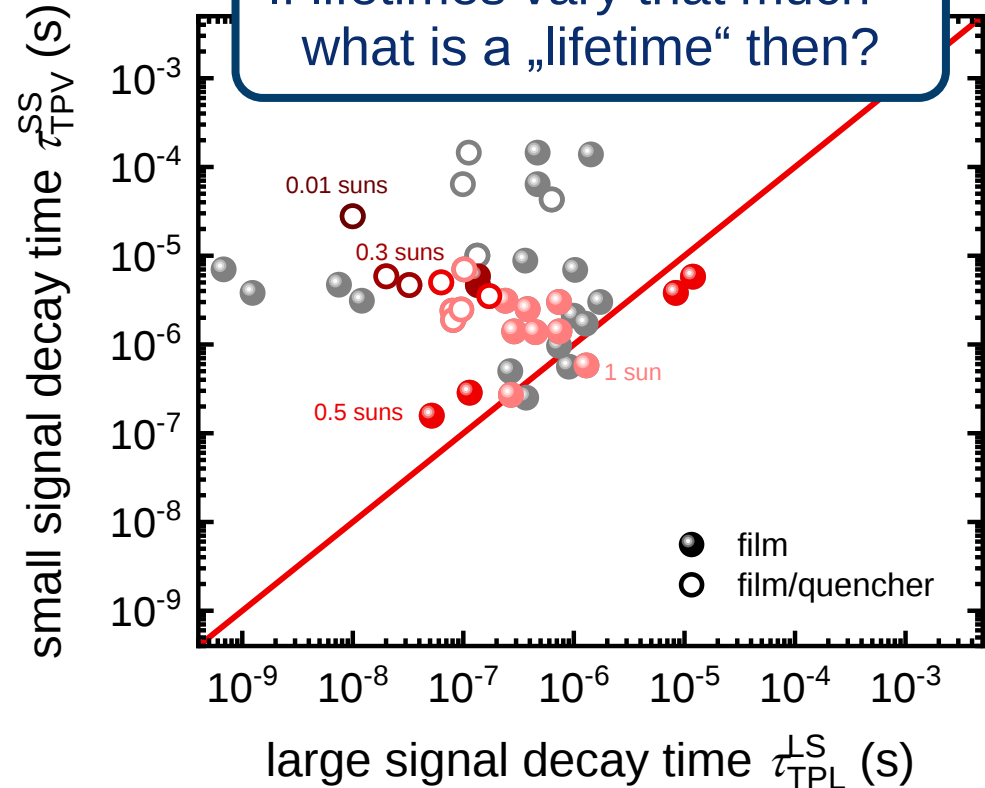
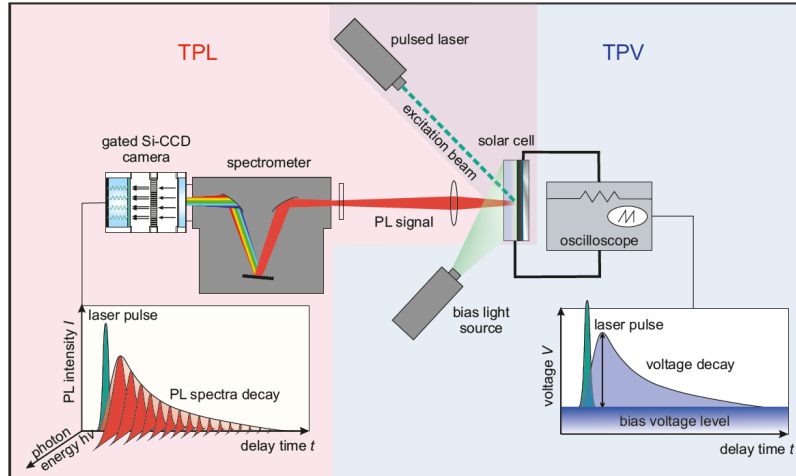
Metaanalysis: TPV vs. TPL

Fairly poor correlation between the two decay times. Why?

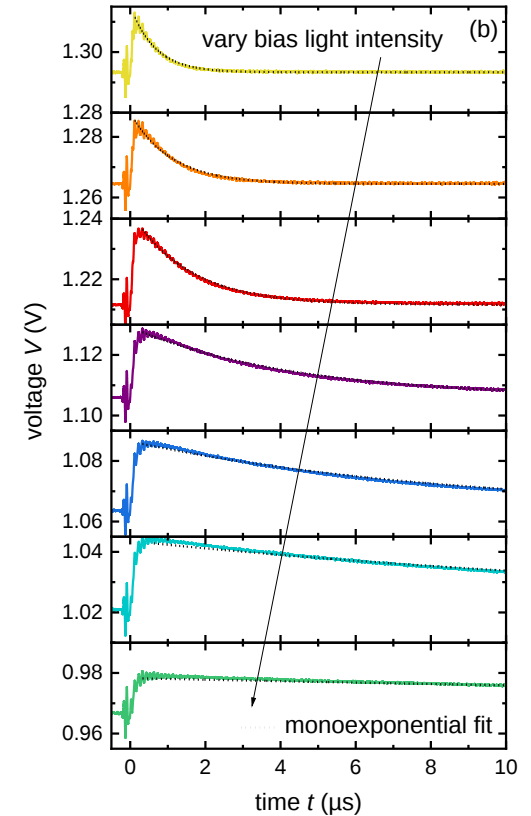
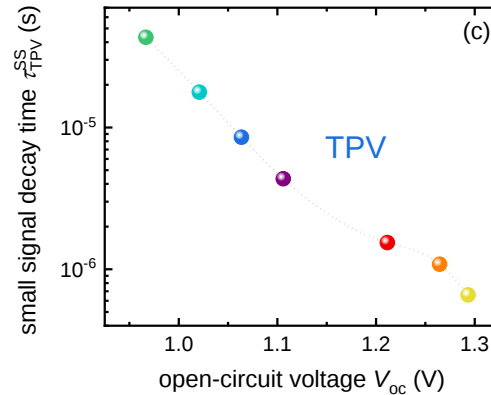
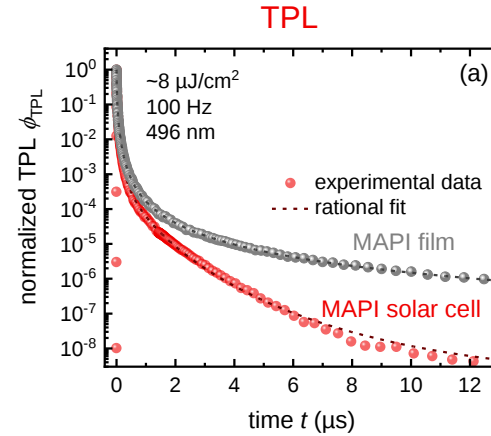
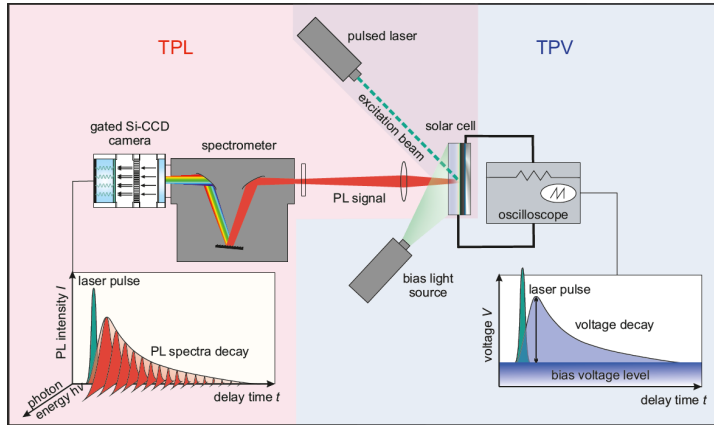


Metaanalysis: TPV vs. TPL

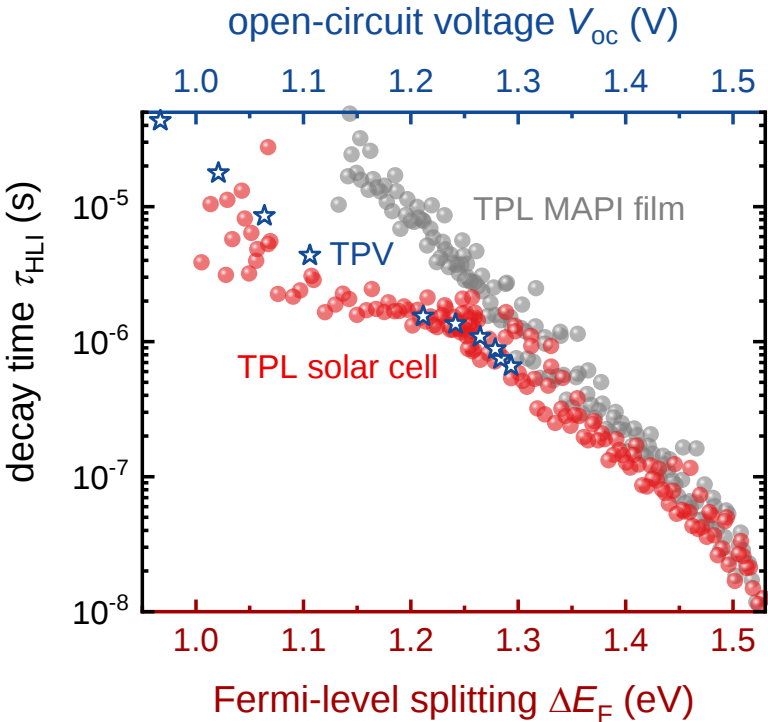
Fairly poor correlation between the two decay times. Why?



What is typically measured?



How to make sense out of it

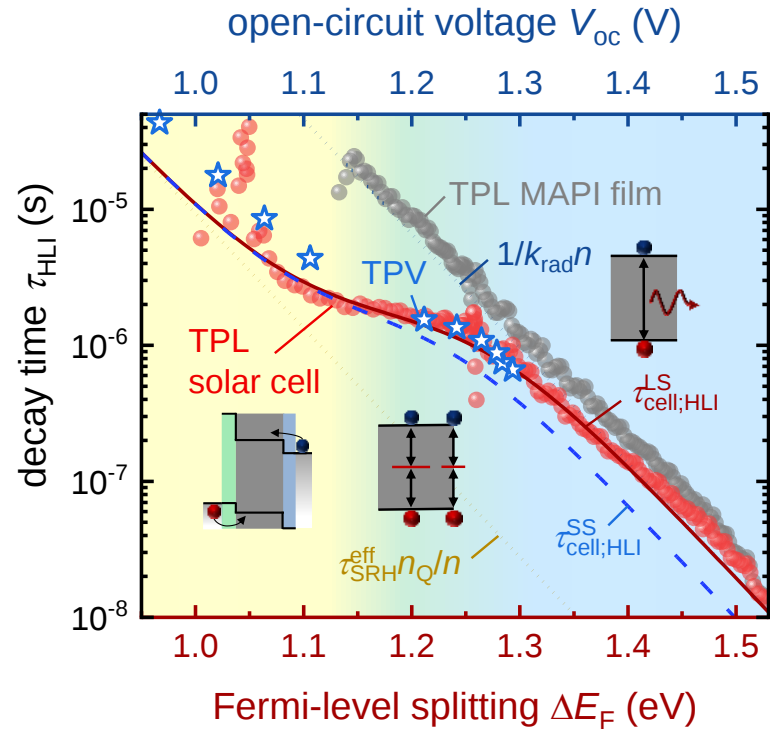


$$\frac{dn(t)}{dt} = -k_{\text{rad}} n(t)^2 - \frac{n(t)}{\tau_{\text{SRH}}^{\text{bulk}}} - \frac{C_{\text{area}}}{qd_{\text{pero}}} \frac{dV_{\text{ext}}(t)}{dt} + G$$

$$\tau_{\text{cell, HLI}}^{\text{LS}} = -\frac{n(t)}{dn(t)/dt} = \frac{n_Q/n(t) + 1}{k_{\text{rad}} n(t) + 1/\tau_{\text{SRH}}^{\text{eff}}}$$

$$n_Q = 2C_{\text{area}} k_B T / (q^2 d_{\text{pero}})$$

How to make sense out of it



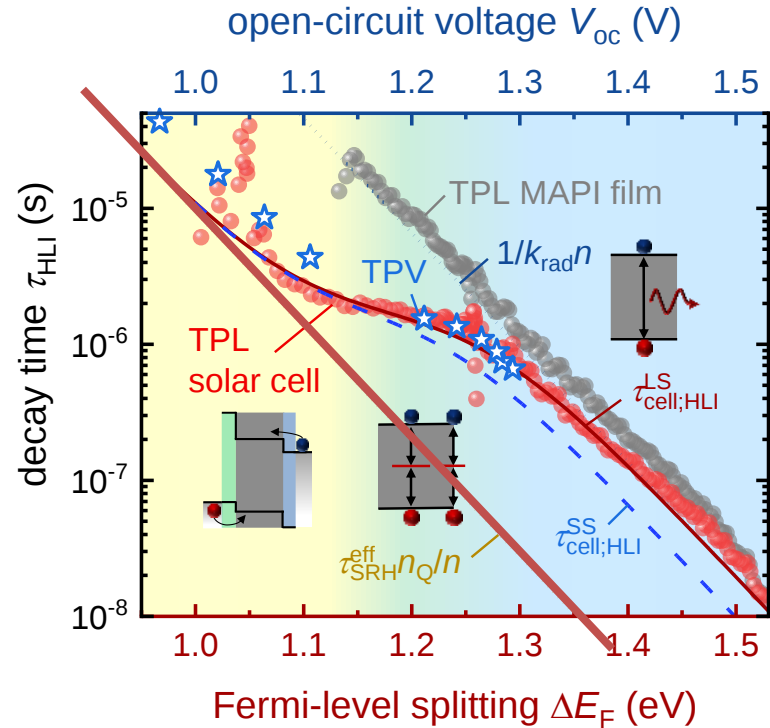
Capacitive charging of the electrodes

$$\frac{dn(t)}{dt} = -k_{rad}n(t)^2 - \frac{n(t)}{\tau_{SRH}^{bulk}} - \left[\frac{C_{area}}{qd_{pero}} \frac{dV_{ext}(t)}{dt} \right] + G$$

$$\tau_{cell, HLI}^{LS} = -\frac{n(t)}{dn(t)/dt} = \frac{n_Q/n(t) + 1}{k_{rad}n(t) + 1/\tau_{SRH}^{eff}}$$

$$n_Q = 2C_{area}k_B T / (q^2 d_{pero})$$

How to make sense out of it

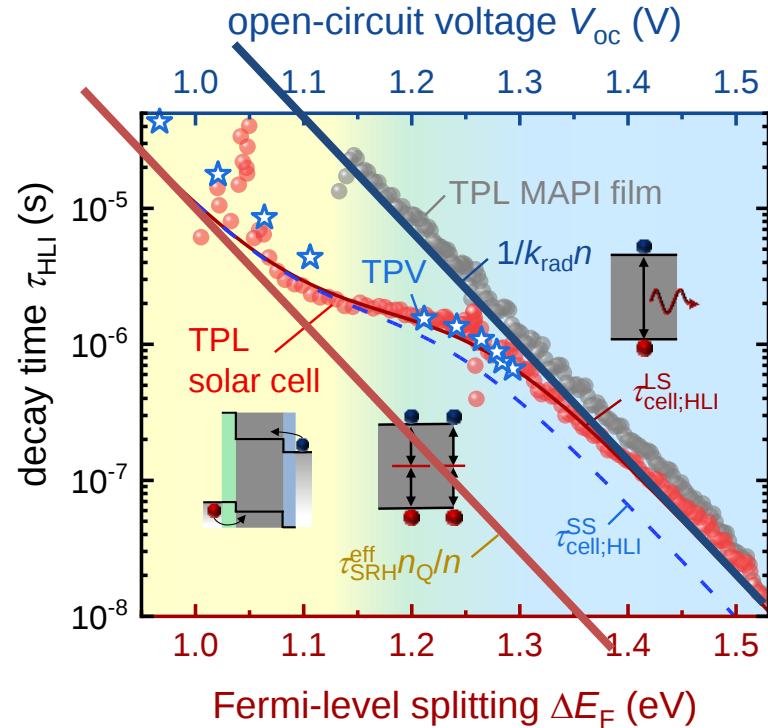


$$\frac{dn(t)}{dt} = -k_{rad}n(t)^2 - \frac{n(t)}{\tau_{SRH}^{bulk}} - \frac{C_{area}}{qd_{pero}} \frac{dV_{ext}(t)}{dt} + G$$

$$\tau_{cell,HLI}^{LS} = -\frac{n(t)}{dn(t)/dt} = \frac{n_Q/n(t)+1}{k_{rad}n(t)+1/\tau_{SRH}^{eff}}$$

$$n_Q = 2C_{area}k_B T / (q^2 d_{pero})$$

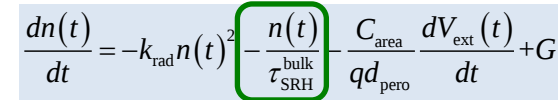
How to make sense out of it



$$\frac{dn(t)}{dt} = -k_{rad}n(t)^2 - \frac{n(t)}{\tau_{SRH}^{bulk}} - \frac{C_{area}}{qd_{pero}} \frac{dV_{ext}(t)}{dt} + G$$

$$\tau_{cell, HLI}^{LS} = -\frac{n(t)}{dn(t)/dt} = \frac{n_Q/n(t)+1}{k_{rad}n(t)+1/\tau_{SRH}^{eff}}$$

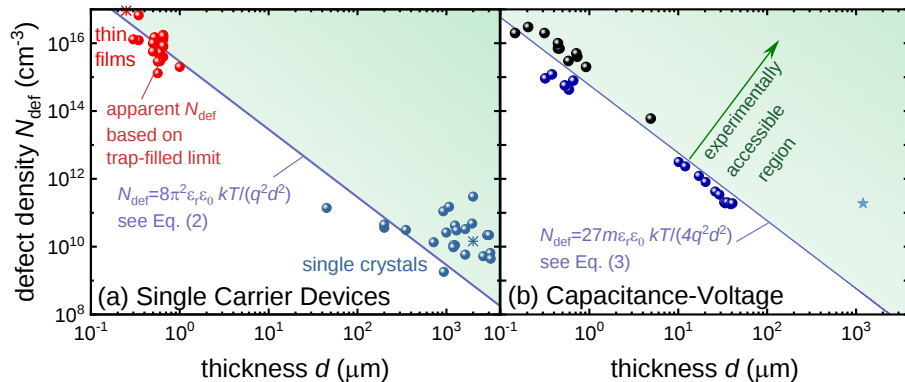
$$n_Q = 2C_{area}k_B T / (q^2 d_{pero})$$



$$\tau_{\text{cell, HLI}}^{\text{LS}} = -\frac{n(t)}{dn(t)/dt} = \frac{n_Q}{k_{\text{rad}} n(t) + 1} \tau_{\text{SRH}}^{\text{eff}}$$

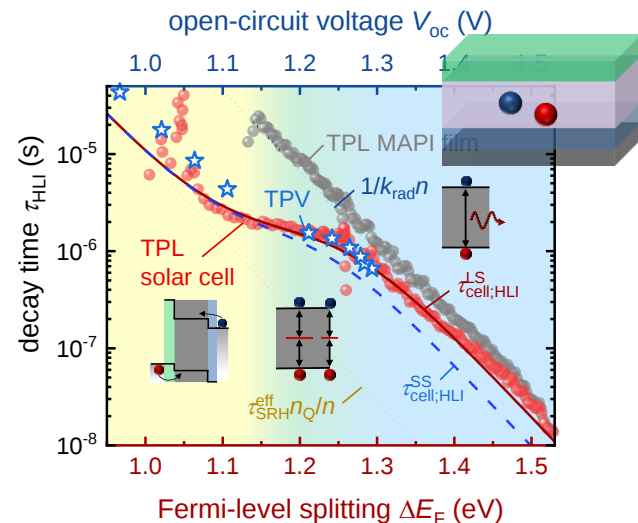
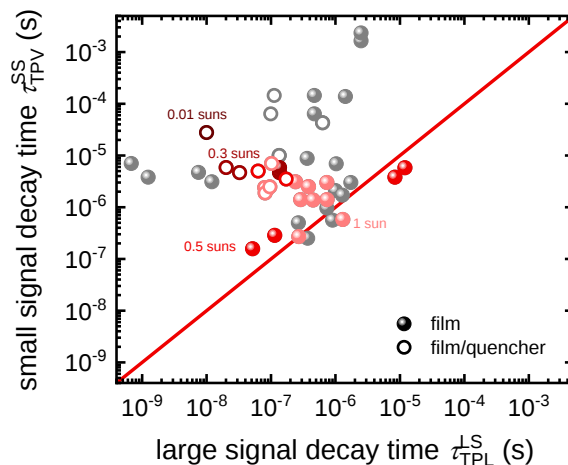
$$n_Q = 2C_{\text{area}} k_B T / (q^2 d_{\text{pero}})$$

Summary



1) Beware of detection thresholds, when measuring defect densities

2) Huge method to method variation in “lifetimes” results from voltage dependence of decay times



Thanks to

Johanna Siekmann, Sandheep Ravishankar, Lisa Krückemeier, and Uwe Rau
and

Helmholtz Association for Funding

Apparent Defect Densities in Halide Perovskite Thin Films and Single Crystals



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Consistent Interpretation of Electrical and Optical Transients in Halide Perovskite Layers and Solar Cells

Lisa Krückemeier, Zhifa Liu, Benedikt Krogmeier, Uwe Rau,* and Thomas Kirchartz**

Thank you for your attention